## Reduction-Phase-Time Dependence of Atmospheric-Pressure-Plasma Nitriding for Stainless Steel

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Stainless steel has excellent corrosion resistance and is used in many industries. In order to improve mechanical properties of stainless steel, we are studying the nitriding treatment using atmosphericpressure-plasma jet for stainless steel as our unique technology. It is necessary to reduce the passive film to perform nitriding stainless steels. We found that N atoms can be diffused into the sample by adding H<sub>2</sub> gas to the N<sub>2</sub> operating gas [1]. As a new method, the process divided into a "reduction phase" in which 5% of H<sub>2</sub> is added to increase efficiency of reduction of the passive film and "nitridation phase" in which H<sub>2</sub> is reduced to 1% to increase the NH density. We expect that the thickness can be increased by performing this two-step process as compared to the conventional nitriding process of the nitridation-phase only. In this research, we investigated the reduction-phase-time dependence of N<sub>2</sub> diffusion into stainless steel.

Fig. 1 shows a schematic of the experimental device. A pulsed-arc plasma jet was sprayed onto sample surface in a simple quartz cover. The sample is JIS SUS304 ( $20 \times 20 \times 4 \text{ mm}^3$ ). The total treatment time was 2 h, and the reduction-phase time was changed from 0 to 2 h.

Fig.2 shows the reduction-phase-time dependence of the thickness and surface hardness of the hardened layer. Both the thickness and surface hardness tended to decrease as the reduction-phase-time increased. As a result, we found that the  $H_2$  in the nitridation-phase was enough to reduce passive film. Decrease of thickness is likely due to decrease in NH density.

## **REFERENCES:**

[1] A. Maeda et al., Proc. XXXIII Intl. Conf. Phenomena in Ionized Gases, 169 (2017).



Fig.1 Schematic of experimental device.



